

**SCOPE: DUAL POWER MOSFET DRIVER**

<u>Device Type</u>	<u>Generic Number</u>	<u>Circuit Function</u>
01	MAX626M(x)/883B	Dual Power Inverting MOSFET Driver
02	MAX627M(x)/883B	Dual Power Noninverting MOSFET Driver
03	MAX628M(x)/883B	Dual Power Inverting/Noninverting MOSFET Driver
04	TSC426M(x)/883B	Dual Power Inverting MOSFET Driver
05	TSC427M(x)/883B	Dual Power Noninverting MOSFET Driver
06	TSC428M(x)/883B	Dual Power Inverting/Noninverting MOSFET Driver

**Case Outline(s).** The case outlines shall be designated in Mil-Std-1835 and as follows:

<u>Outline Letter</u>	<u>Mil-Std-1835</u>	<u>Case Outline</u>	<u>Package Code</u>
JA	GDIP1-T8 or CDIP2-T8	8 LEAD CERDIP	J8
NP	QCQC1-N20	20 Leadless Carrier	L20

**Absolute Maximum Ratings**

Supply Voltage $V_{DD}$ to GND .....	20V
Input Voltage .....	$V_{DD} + 0.3V$ to GND $-0.3V$
Output Current (per pin, capacitive load) .....	1.5A
Peak Supply Current or GND Current (per pin) .....	3.0A

Lead Temperature (soldering, 10 seconds) .....	+300°C
Storage Temperature .....	-65°C to +150°C

Continuous Power Dissipation .....	$T_A = +70^\circ C$
8 pin CERDIP(derate 8.0mW/°C above +70°C) .....	640mW
20 pin LCC(derate 9.1mW/°C above +70°C) .....	727mW
Junction Temperature $T_J$ .....	+150°C
Thermal Resistance, Junction to Case, $\theta_{JC}$	
8 pin CERDIP .....	55°C/W
20 pin LCC .....	20°C/W
Thermal Resistance, Junction to Ambient, $\theta_{JA}$ :	
8 pin CERDIP .....	125°C/W
20 pin LCC .....	110°C/W

**Recommended Operating Conditions**

Ambient Operating Range ( $T_A$ ) .....	-55°C to +125°C
Supply Voltage Range .....	$4.5V \leq V_{DD} \leq 18V$

**ORDERING INFORMATION:**

Package	Device	Part #	Device	Part #
8 pin CERDIP	01	MAX626MJA/883B	04	TSC426MJA/883B
20 pin LCC	01	MAX626MNP/883B	04	TSC426MNP/883B
8 pin CERDIP	02	MAX627MJA/883B	05	TSC427MJA/883B
20 pin LCC	02	MAX627MNP/883B	05	TSC427MNP/883B
8 pin CERDIP	03	MAX628MJA/883B	06	TSC428MJA/883B
20 pin LCC	03	MAX628MNP/883B	06	TSC428MNP/883B

Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**TABLE 1. ELECTRICAL TESTS:**

TEST	Symbol	CONDITIONS		Group A Subgroup	Device type	Limits Min	Limits Max	Units
		-55 °C ≤ T <sub>A</sub> ≤ +125 °C +4.5V ≤ V <sub>DD</sub> ≤ 18V Unless otherwise specified						
Logic 1 Input Voltage	V <sub>IH</sub>			1,2,3	All	2.4		V
Logic 0 Input Voltage	V <sub>IL</sub>			1,2,3	All		0.8	V
Input Voltage Range	V <sub>IN(max)</sub>			1,2,3	All	0	V <sub>DD</sub>	V
Input Current	I <sub>IN</sub>	V <sub>IN</sub> = 0V to 18V		1 2,3	All		±1 ±10	µA
Output High Voltage	V <sub>OH</sub>	R <sub>L</sub> = ∞		1,2,3	All	V <sub>DD</sub> -25		mV
Output Low Voltage	V <sub>OL</sub>	R <sub>L</sub> = ∞		1,2,3	All		25	mV
Output Resistance	R <sub>OUT</sub>	V <sub>DD</sub> = 18V, I <sub>OUT</sub> = 10mA NOTE 3, NOTE 4		1,2 3	All		20 15	Ω
Power Supply Current	I <sub>S1</sub>	V <sub>IN</sub> = +3V, both inputs		1,2 3	All		8 12	mA
Power Supply Current	I <sub>S2</sub>	V <sub>IN</sub> = 0V, both inputs		1,2 3	All		0.4 0.6	mA
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = 18V	NOTE 2	9 10,11 10,11	All 01,02,03 04,05,06		30 40 60	ns
Fall Time	t <sub>f</sub>	V <sub>DD</sub> = 18V	NOTE 2	9 10,11	All		30 40	ns
Delay Time	t <sub>D1</sub>	V <sub>DD</sub> = 18V	NOTE 2	9 10,11	01,02,03		30 40	ns
				9 10,11	04,05,06		40 60	
Delay Time	t <sub>D2</sub>	V <sub>DD</sub> = 18V	NOTE 2	9 10,11	01,02,03		50 75	ns
				9 10,11	04,05,06		60 120	

NOTE 1: Guaranteed by design.

NOTE 2: Subgroups 10 and 11 are guaranteed if not tested to the limits specified in Table 1.

NOTE 3: V<sub>IN</sub> = 0.8V for inverting stages, V<sub>IN</sub> = 2.4V for noninverting stages.

NOTE 4: V<sub>IN</sub> = 2.4V for inverting stages, V<sub>IN</sub> = 0.8V for noninverting stages.

**TERMINAL CONNECTIONS FOR 01, 02, 03, 04, 05, 06**

8 PIN CERDIP				20 PIN LCC							
	01,04	02,05	03,06		01,04	02,05	03,06		01,04	02,05	03,06
1	NC	NC	NC	1	NC	NC	NC	11	NC	NC	NC
2	INA	INA	INA	2	NC	NC	NC	12	NC	NC	NC
3	GND	GND	GND	3	NC	NC	NC	13	NC	NC	NC
4	INB	INB	INB	4	INA	INA	INA	14	_____	OUTB	OUTB
5	_____	OUTB	OUTB	5	NC	NC	NC	15	NC	NC	NC
6	V <sub>DD</sub>	V <sub>DD</sub>	V <sub>DD</sub>	6	GND	GND	GND	16	V <sub>DD</sub>	V <sub>DD</sub>	V <sub>DD</sub>
7	_____	OUTA	_____	7	NC	NC	NC	17	NC	NC	NC
8	NC	NC	NC	8	INB	INB	INB	18	_____	OUTA	_____
				9	NC	NC	NC	19	NC	NC	NC
				10	NC	NC	NC	20	NC	NC	NC

**QUALITY ASSURANCE**

Sampling and inspection procedures shall be in accordance with MIL-Prf-38535, Appendix A as specified in Mil-Std-883.

Screening shall be in accordance with Method 5004 of Mil-Std-883. Burn-in test Method 1015:

1. Test Condition, A, B, C, or D.
2. TA = +125°C minimum.
3. Interim and final electrical test requirements shall be specified in Table 2.

Quality conformance inspection shall be in accordance with Method 5005 of Mil-Std-883, including Groups A, B, C, and D inspection.

Group A inspection:

1. Tests as specified in Table 2.
2. Selected subgroups in Table 1, Method 5005 of Mil-Std-883 shall be omitted.

Group C and D inspections:

- a. End-point electrical parameters shall be specified in Table 1.
- b. Steady-state life test, Method 1005 of Mil-Std-883:
  1. Test condition A, B, C, D.
  2. TA = +125°C, minimum.
  3. Test duration, 1000 hours, except as permitted by Method 1005 of Mil-Std-883.

**TABLE 2. ELECTRICAL TEST REQUIREMENTS**

Mil-Std-883 Test Requirements	Subgroups per Method 5005, Table 1
Interim Electric Parameters Method 5004	1
Final Electrical Parameters Method 5005	1*, 2, 3, 9, 10**, 11**
Group A Test Requirements Method 5005	1, 2, 3, 9, 10**, 11**
Group C and D End-Point Electrical Parameters Method 5005	1

\* PDA applies to Subgroup 1 only.

\*\* Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits of Table 1.